

FDP5690/FDB5690

60V N-Channel PowerTrench™ MOSFET

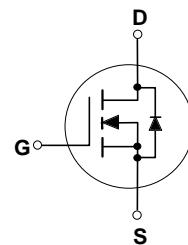
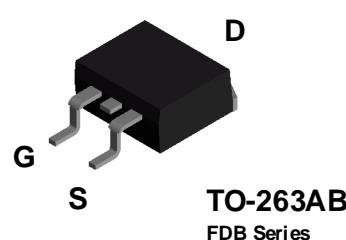
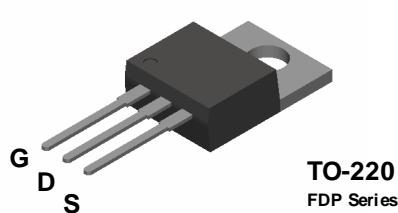
General Description

This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers.

These MOSFETs feature faster switching and lower gate charge than other MOSFETs with comparable $R_{DS(on)}$ specifications resulting in DC/DC power supply designs with higher overall efficiency.

Features

- 32 A, 60 V. $R_{DS(ON)} = 0.027 \Omega$ @ $V_{GS} = 10$ V
 $R_{DS(ON)} = 0.032 \Omega$ @ $V_{GS} = 6$ V.
- Critical DC electrical parameters specified at elevated temperature.
- Rugged internal source-drain diode can eliminate the need for an external Zener diode transient suppressor.
- High performance trench technology for extremely low $R_{DS(ON)}$.
- 175°C maximum junction temperature rating.



Absolute Maximum Ratings

$T_c = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	FDP5690	FDB5690	Units
V_{DSS}	Drain-Source Voltage	60		V
V_{GSS}	Gate-Source Voltage		± 20	V
I_D	Maximum Drain Current - Continuous	32	100	A
	- Pulsed			
P_D	Total Power Dissipation @ $T_c = 25^\circ\text{C}$	58	0.4	W
	Derate above 25°C			
T_J, T_{STG}	Operating and Storage Junction Temperature Range	-65 to +175		°C

Thermal Characteristics

R_{JJC}	Thermal Resistance, Junction-to-Case	2.6	°C/W
R_{JJA}	Thermal Resistance, Junction-to-Ambient	62.5	°C/W

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape Width	Quantity
FDB5690	FDB5690	13"	24mm	800
FDP5690	FDP5690	Tube	N/A	45

Electrical Characteristics $T_c = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Tvp	Max	Units
--------	-----------	-----------------	-----	-----	-----	-------

Drain-Source Avalanche Ratings (Note1)

W_{DSS}	Single Pulse Drain-Source Avalanche Energy	$V_{DD} = 30\text{ V}$, $I_D = 32\text{ A}$			80	mJ
I_{AR}	Maximum Drain-Source Avalanche Current				32	A

Off Characteristics

BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0\text{ V}$, $I_D = 250\text{ }\mu\text{A}$	60			V
ΔBV_{DSS} ΔT_J	Breakdown Voltage Temperature Coefficient	$I_D = 250\text{ }\mu\text{A}$, Referenced to 25°C		61		$\text{mV/}^\circ\text{C}$
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 48\text{ V}$, $V_{GS} = 0\text{ V}$			1	μA
I_{GSSF}	Gate-Body Leakage Current, Forward	$V_{GS} = 20\text{ V}$, $V_{DS} = 0\text{ V}$			100	nA
I_{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = -20\text{ V}$, $V_{DS} = 0\text{ V}$			-100	nA

On Characteristics (Note 1)

$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 250\text{ }\mu\text{A}$	2	2.4	4	V
$\Delta V_{GS(th)}$ ΔT_J	Gate Threshold Voltage Temperature Coefficient	$I_D = 250\text{ }\mu\text{A}$, Referenced to 25°C		-6.4		$\text{mV/}^\circ\text{C}$
$R_{DS(on)}$	Static Drain-Source On-Resistance	$V_{GS} = 10\text{ V}$, $I_D = 16\text{ A}$, $V_{GS} = 10\text{ V}$, $I_D = 16\text{ A}$, $T_J = 125^\circ\text{C}$ $V_{GS} = 6\text{ V}$, $I_D = 15\text{ A}$	0.021 0.042 0.024	0.027 0.055 0.032		Ω
$I_{D(on)}$	On-State Drain Current	$V_{GS} = 10\text{ V}$, $V_{DS} = 5\text{ V}$	50			A
g_{FS}	Forward Transconductance	$V_{DS} = 5\text{ V}$, $I_D = 16\text{ A}$		32		S

Dynamic Characteristics

C_{iss}	Input Capacitance	$V_{DS} = 25\text{ V}$, $V_{GS} = 0\text{ V}$, $f = 1.0\text{ MHz}$	1120		pF
C_{oss}	Output Capacitance		160		pF
C_{rss}	Reverse Transfer Capacitance		80		pF

Switching Characteristics (Note 1)

$t_{d(on)}$	Turn-On Delay Time	$V_{DD} = 30\text{ V}$, $I_D = 1\text{ A}$, $V_{GS} = 10\text{ V}$, $R_{GEN} = 6\text{ }\Omega$	10	18	ns
t_r	Turn-On Rise Time		9	18	ns
$t_{d(off)}$	Turn-Off Delay Time		24	39	ns
t_f	Turn-Off Fall Time		10	18	ns
Q_g	Total Gate Charge	$V_{DS} = 15\text{ V}$, $I_D = 16\text{ A}$, $V_{GS} = 10\text{ V}$	23	33	nC
Q_{gs}	Gate-Source Charge		3.9		nC
Q_{gd}	Gate-Drain Charge		6.8		nC

Drain-Source Diode Characteristics and Maximum Ratings

I_S	Maximum Continuous Drain-Source Diode Forward Current	(Note 1)			32	A
V_{SD}	Drain-Source Diode Forward Voltage		$V_{GS} = 0\text{ V}$, $I_S = 16\text{ A}$	(Note 1)	0.92	1.2

Note:

1. Pulse Test: Pulse Width $\leq 300\text{ }\mu\text{s}$, Duty Cycle $\leq 2.0\%$

Typical Characteristics

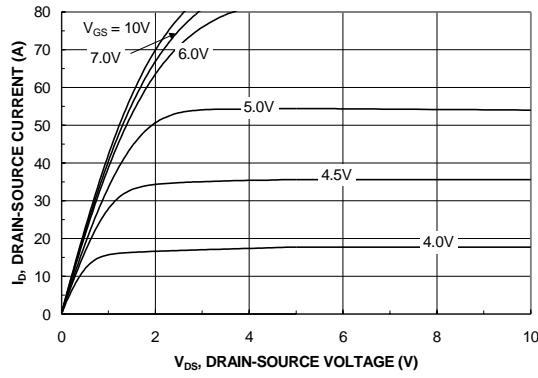


Figure 1. On-Region Characteristics.

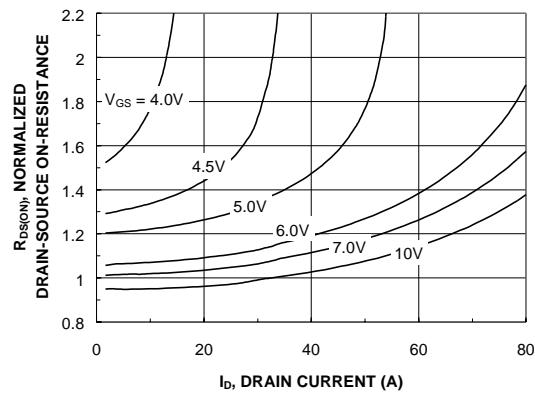


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

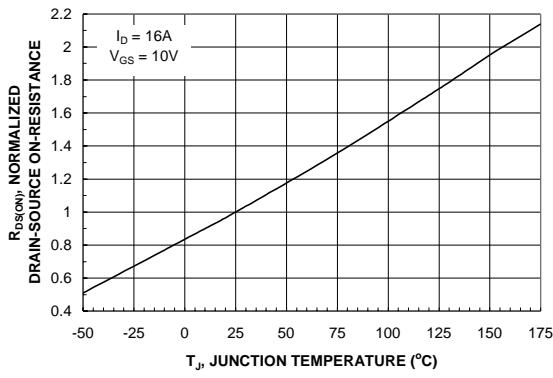


Figure 3. On-Resistance Variation with Temperature.

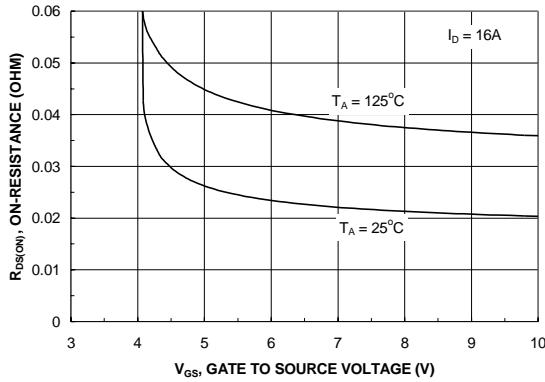


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

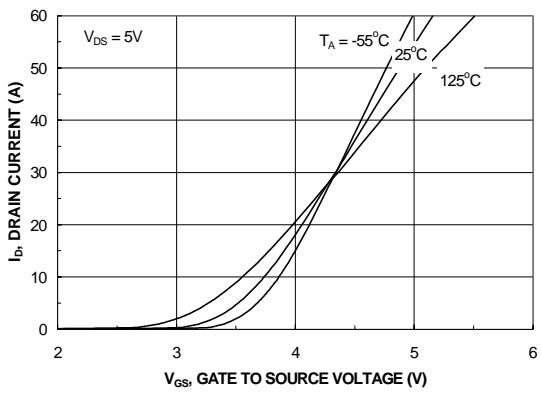


Figure 5. Transfer Characteristics.

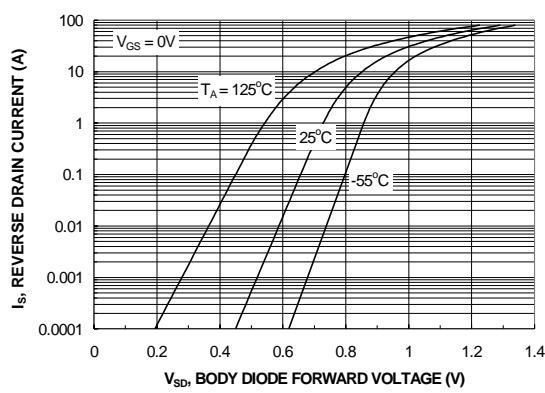


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics (continued)

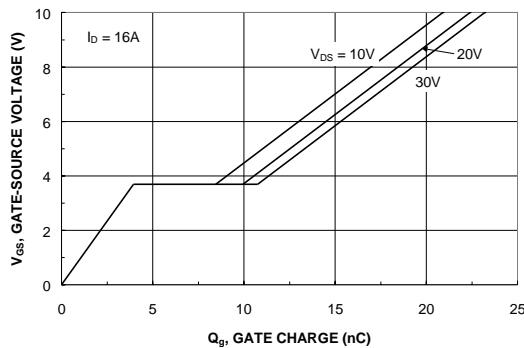


Figure 7. Gate-Charge Characteristics.

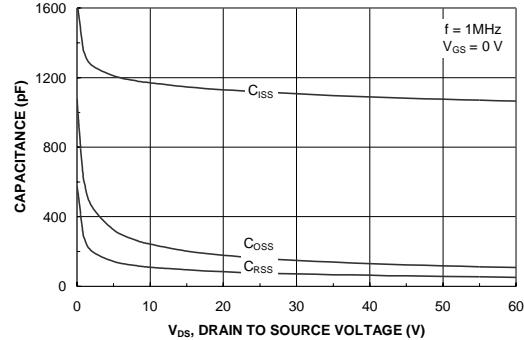


Figure 8. Capacitance Characteristics.

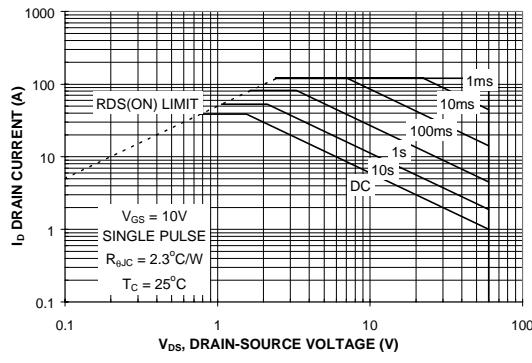


Figure 9. Maximum Safe Operating Area.

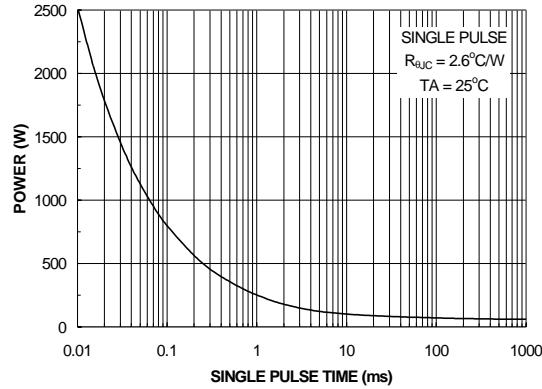


Figure 10. Single Pulse Maximum Power Dissipation.

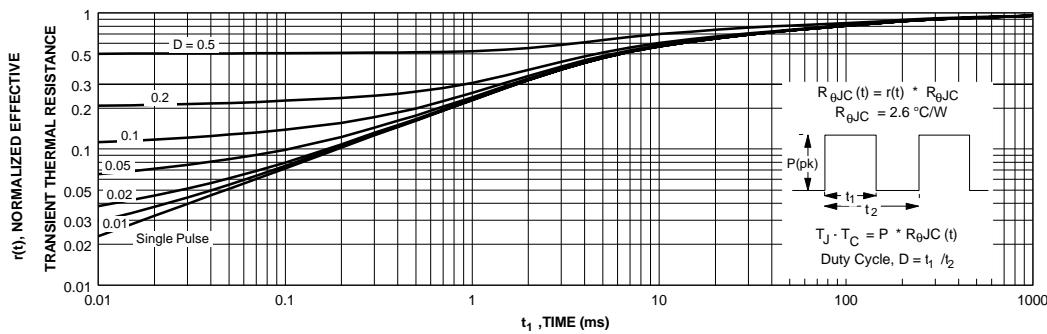


Figure 11. Transient Thermal Response Curve.

TRADEMARKS

The following are registered and unregistered trademarks Fairchild Semiconductor owns or is authorized to use and is not intended to be an exhaustive list of all such trademarks.

ACE TM	HiSeC TM	SuperSOT TM -8
Bottomless TM	ISOPLANAR TM	SyncFET TM
CoolFET TM	MICROWIRE TM	TinyLogic TM
CROSSVOLT TM	POP TM	UHC TM
E ² CMOS TM	PowerTrench [®]	VCX TM
FACT TM	QFET TM	
FACT Quiet Series TM	QST TM	
FAST [®]	Quiet Series TM	
FAST TM	SuperSOT TM -3	
GTO TM	SuperSOT TM -6	

DISCLAIMER

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION OR DESIGN. FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS.

LIFE SUPPORT POLICY

FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION. As used herein:

1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, or (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in significant injury to the user.
2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

PRODUCT STATUS DEFINITIONS

Definition of Terms

Datasheet Identification	Product Status	Definition
Advance Information	Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	This datasheet contains preliminary data, and supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
No Identification Needed	Full Production	This datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
Obsolete	Not In Production	This datasheet contains specifications on a product that has been discontinued by Fairchild semiconductor. The datasheet is printed for reference information only.